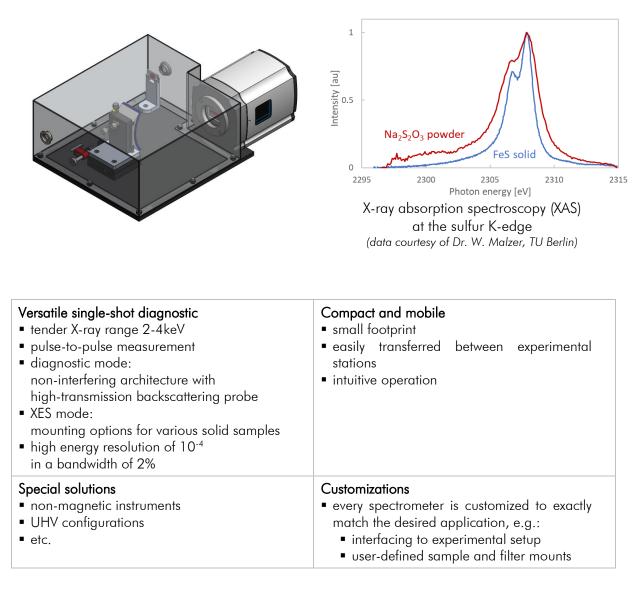
H+P SPECTROSCOPY SCIENTIFIC INSTRUMENTATION

hardLIGHT TXS **Tender X-ray Spectrometer**

Our novel TXS spectrometer enables accurate photon diagnostics at HHG beamlines, X-ray freeelectron lasers, and table-top X-ray lasers. Photon energies between 2 keV and 4 keV can be measured in single-shot. In von Hamos geometry with high-efficiency backscattering, the X-ray spectrum is fingerprinted for online beam characterization. The transmitted beam remains undisturbed with >90% transmission for further use in experiments.

By simply exchanging the backscattering probe with a material sample, the hardLIGHT TXS is made ready for X-ray emission spectroscopy (XES). The tender X-ray range provides sensitive access to the chemical state of many materials, e.g. investigations of sulfur at 2keV allow for important insights for battery research.



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